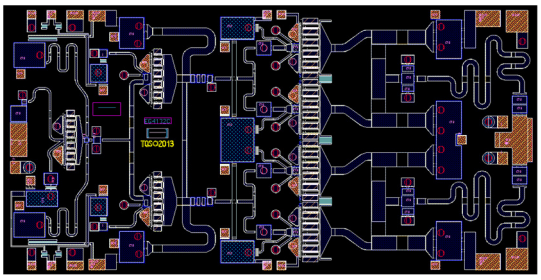
TGA2624

9–10 GHz 18 W GaN Power Amplifier

Applications

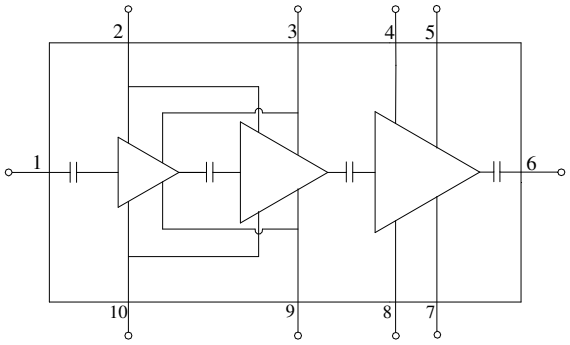
- Weather and Marine Radar.



Product Features

- Frequency Range: 9 – 10GHz
- P_{SAT}: 42.5dBm @ P_{IN} = 15dBm
- P1dB: >38dBm
- PAE: >40% @ P_{IN} = 15dBm
- Large Signal Gain: 27.5dB
- Small Signal Gain: >35dB
- Return Loss: >11dB
- Bias: V_D = 28V, I_{DQ} = 365mA, V_G = -2.7V Typical
- Pulsed V_D: PW = 100us and DC = 10%
- Chip Dimensions: 5.0 x 2.62 x 0.10 mm

Functional Block Diagram



General Description

Qorvo's TGA2624 is an x-band, high power MMIC amplifier fabricated on Qorvo's production 0.25um GaN on SiC process. The TGA2624 operates from 9 – 10GHz and provides a superior combination of power, gain and efficiency. Achieving 18W of saturated output power with 27.5dB of large signal gain and greater than 40% power-added efficiency, the TGA2624 provides the level of performance demanded by today's system architectures. Depending on the system requirements, the TGA2624 can support cost saving initiatives on existing systems while supporting next generation systems with increased performance.

Lead-free and RoHS compliant.

Evaluation boards are available upon request.

Pad Configuration

Pad No.	Symbol
1	RF In
2, 10	V_{G1-2}
4, 8	V_{G3}
3, 9	V_{D1-2}
5, 7	V_{D3}
6	RF Out

Ordering Information

Part	ECCN	Description
TGA2624	3A001.b.2.b.2	9 – 10GHz 18W GaN Power Amplifier

Absolute Maximum Ratings

Parameter	Value
Drain Voltage (V_D)	40V
Gate Voltage Range (V_G)	-5 to 0V
Drain Current (I_{D1-2})	1.6A
Drain Current (I_{D3})	2.1A
Gate Current (I_{G1-2})	-2 to 10mA
Gate Current (I_{G3})	-6 to 14mA
Power Dissipation (P_{DISS}), 85°C	49W
Input Power (P_{IN}), CW, 50Ω, V_D = 28V, 85°C	25dBm
Input Power (P_{IN}), CW, VSWR 6:1, V_D = 28V, 85°C	19dBm
Channel Temperature (T_{CH})	275°C
Mounting Temperature (30 seconds)	320°C
Storage Temperature	-55 to 150°C

Operation of this device outside the parameter ranges given above may cause permanent damage. These are stress ratings only, and functional operation of the device at these conditions is not implied.

Recommended Operating Conditions

Parameter	Value
Drain Voltage (V_D)	28V
Drain Current (I_{DQ})	365mA (Total)
Gate Voltage (V_G)	-2.7V (Typ.)

Electrical specifications are measured at specified test conditions. Specifications are not guaranteed over all recommended operating conditions.

Electrical Specifications

Test conditions unless otherwise noted: 25°C, V_D = 28V, I_{DQ} = 365mA, V_G = -2.7V Typical, Pulsed V_D: PW = 100us, DC = 10%

Parameter	Min	Typical	Max	Units
Operational Frequency Range	9		10	GHz
Small Signal Gain		>35		dB
Input Return Loss		>11		dB
Output Return Loss		>11		dB
Output Power (Pin = 15dBm)		>42.5		dBm
Power Added Efficiency (Pin = 15dBm)		>40		%
Power @ 1dB Compression (P1dB)		>38		dBm
Small Signal Gain Temperature Coefficient		-0.06		dB/°C
Recommended Operating Voltage:	20	28	32	V

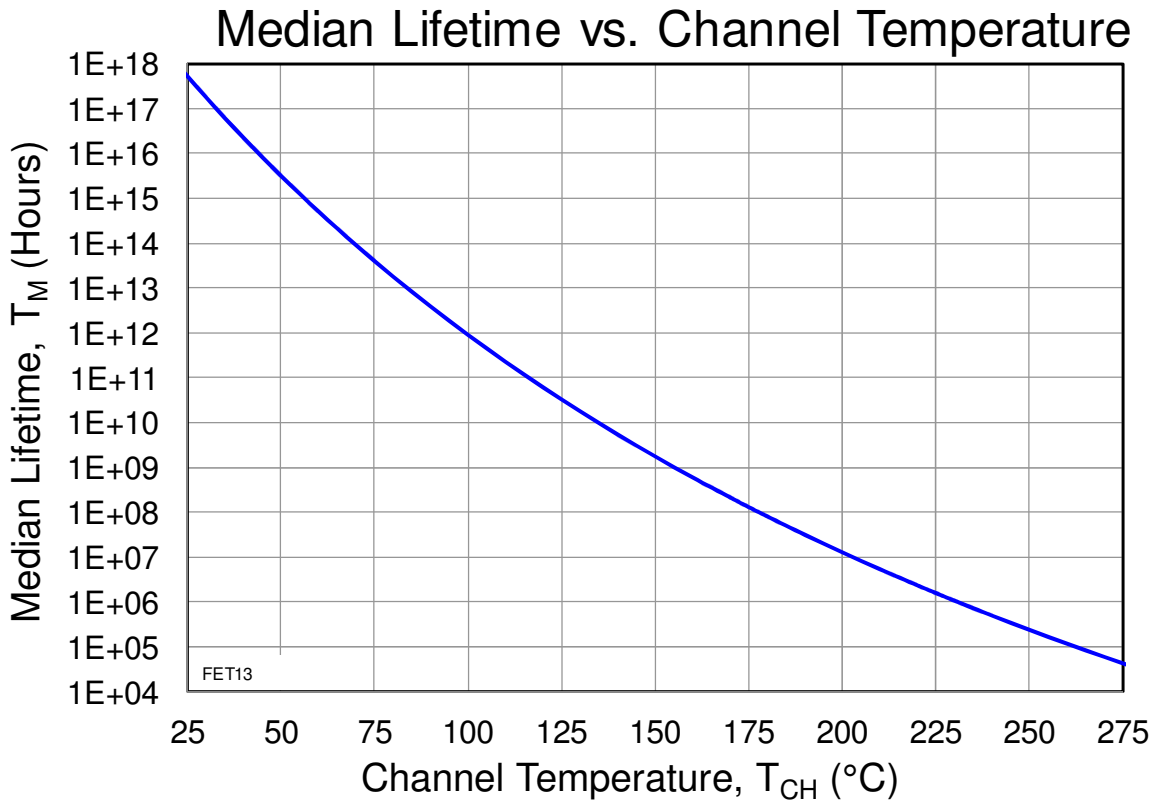
Thermal and Reliability Information

Parameter	Test Conditions	Value	Units
Thermal Resistance (θ_{JC}) (1)	T_{base} = 85°C, Pulsed V_D : PW = 100us, DC = 10%	2.67	°C/W
Channel Temperature (T_{CH}) (Under RF drive)	T_{base} = 85°C, **V_D = 28V**, I_{D_Drive} = 1.7A, P_{IN} = 17dBm, P_{OUT} = 43dBm, P_{DISS} = 29W, Pulsed V_D	162	°C
Median Lifetime (T_M)		4.85 E9	Hrs
Thermal Resistance (θ_{JC}) (1)	T_{base} = 85°C, CW	3.92	°C/W
Channel Temperature (T_{CH}) (Under RF drive)	T_{base} = 85°C, **V_D = 28V**, I_{D_Drive} = 1.55A, P_{IN} = 17dBm, P_{OUT} = 42dBm, P_{DISS} = 28W, CW	195	°C
Median Lifetime (T_M)		1.98 E7	Hrs

Notes:
1. Thermal resistance measured to back of carrier plate. MMIC mounted on 40 mils CuM (85/15) carrier using 1.5 mil AuSn.

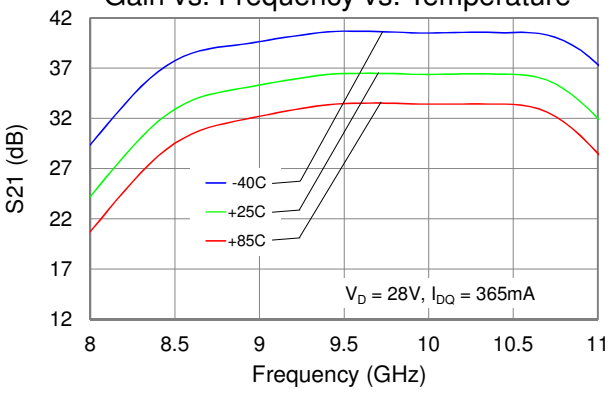
Median Lifetime

Test Conditions: V_D = 40 V; Failure Criteria = 10% reduction in I_{D_MAX}

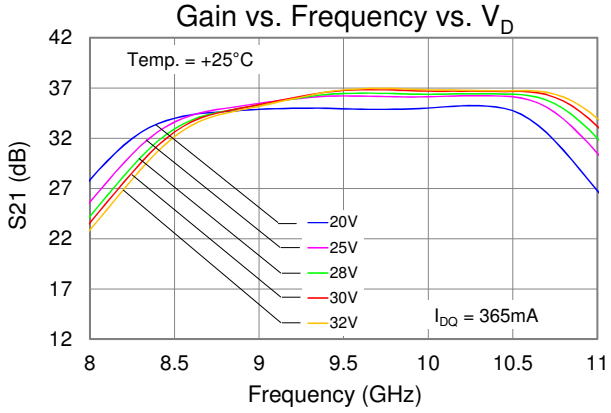


Typical Performance (Small Signal)

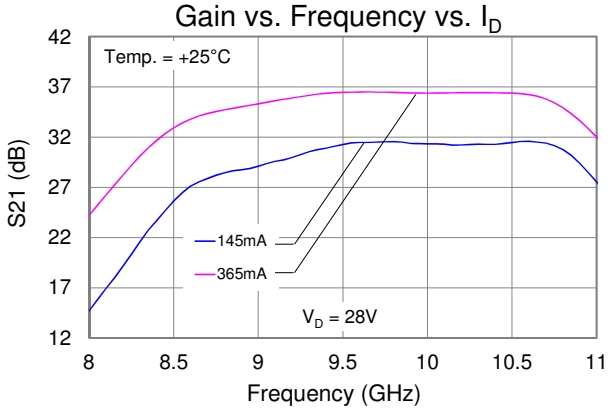
Gain vs. Frequency vs. Temperature



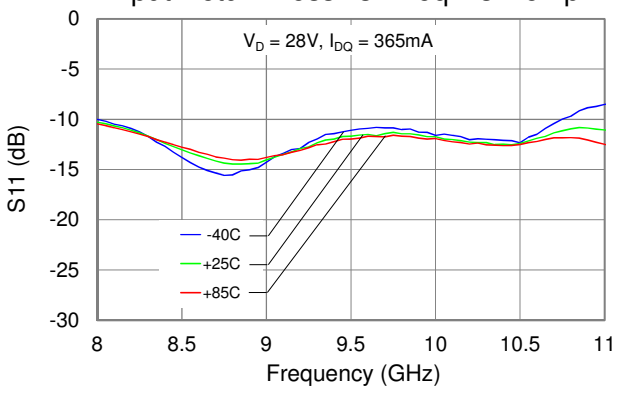
Gain vs. Frequency vs. V_D



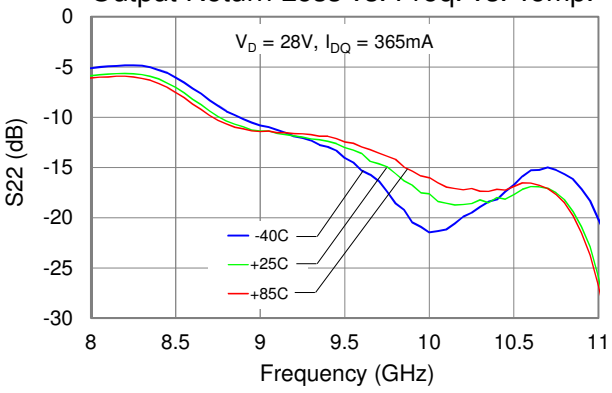
Gain vs. Frequency vs. I_D



Input Return Loss vs. Freq. vs. Temp.

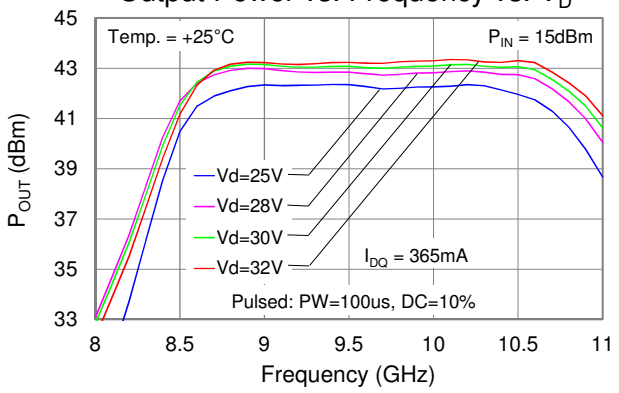


Output Return Loss vs. Freq. vs. Temp.

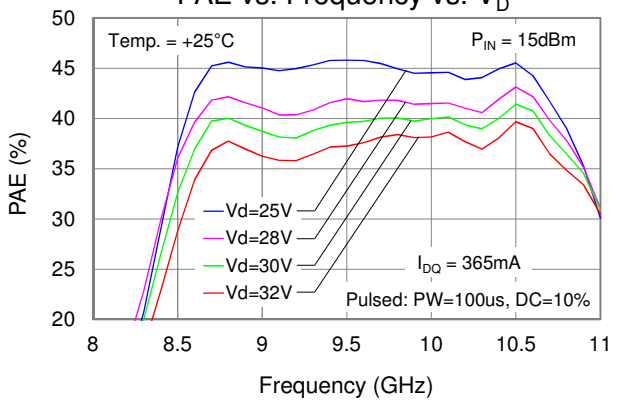


Typical Performance (Pulsed Opeartion)

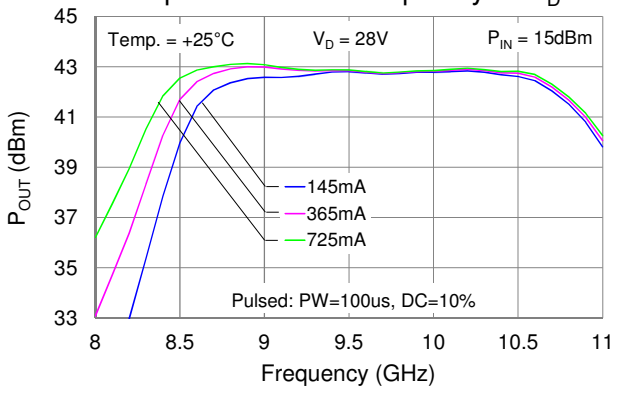
Output Power vs. Frequency vs. V_D



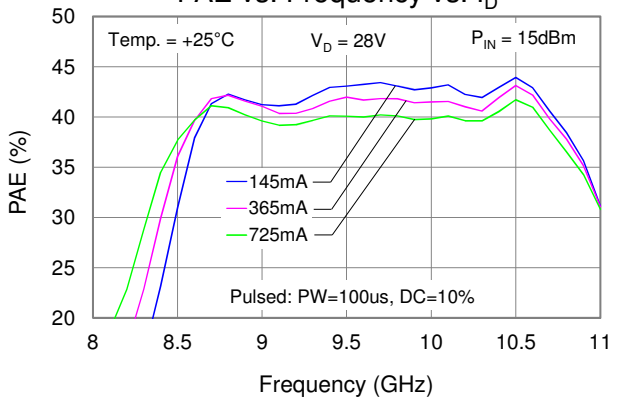
PAE vs. Frequency vs. V_D



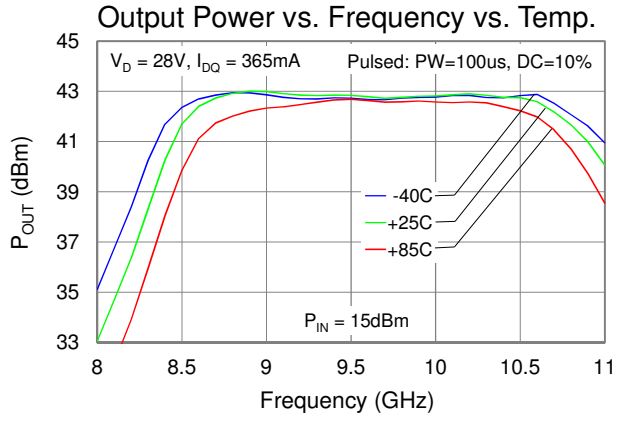
Output Power vs. Frequency vs. I_D



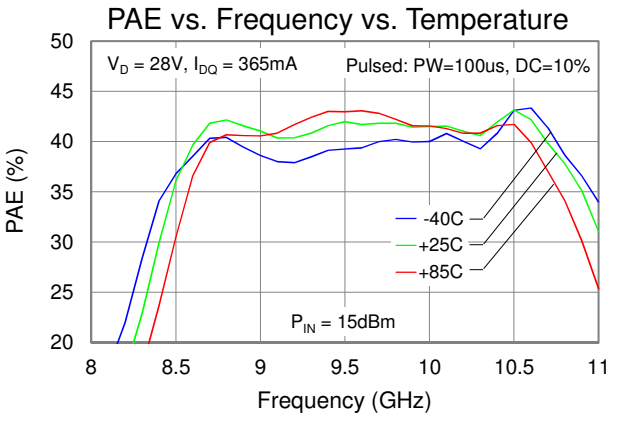
PAE vs. Frequency vs. I_D



Output Power vs. Frequency vs. Temp.

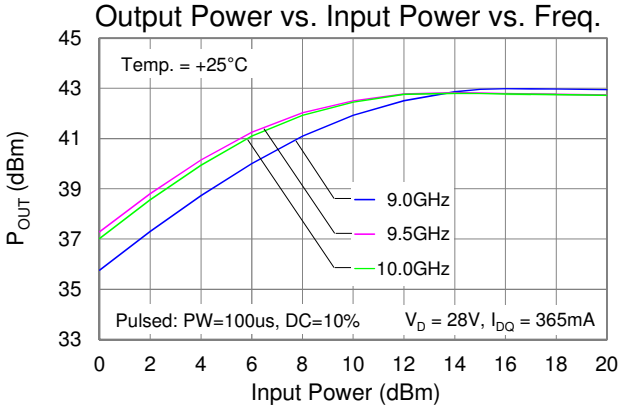


PAE vs. Frequency vs. Temperature

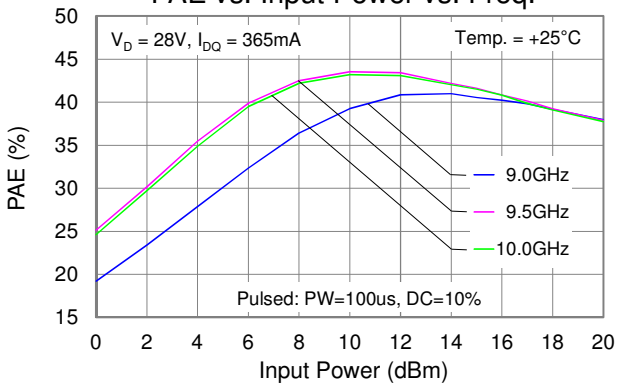


Typical Performance (Pulsed Operation)

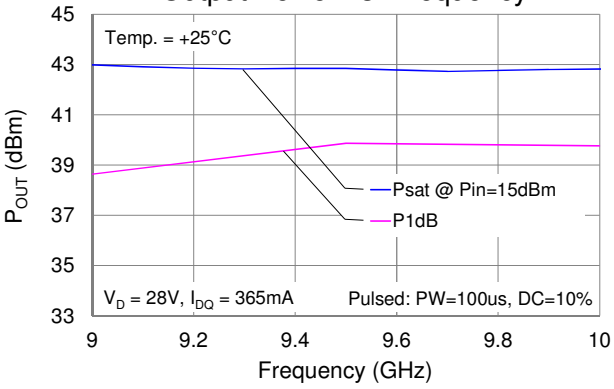
Output Power vs. Input Power vs. Freq.



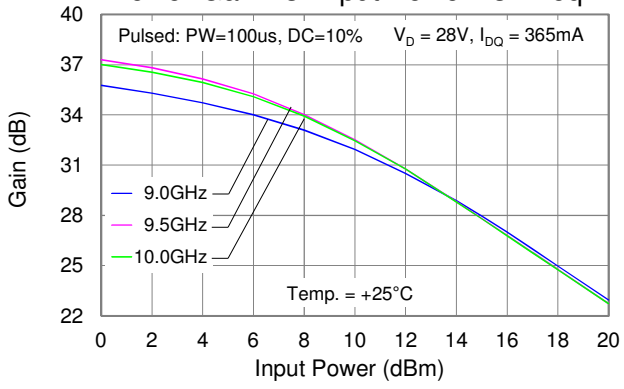
PAE vs. Input Power vs. Freq.



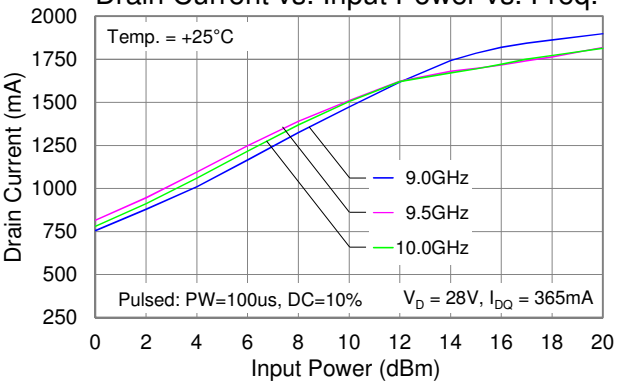
Output Power vs. Frequency



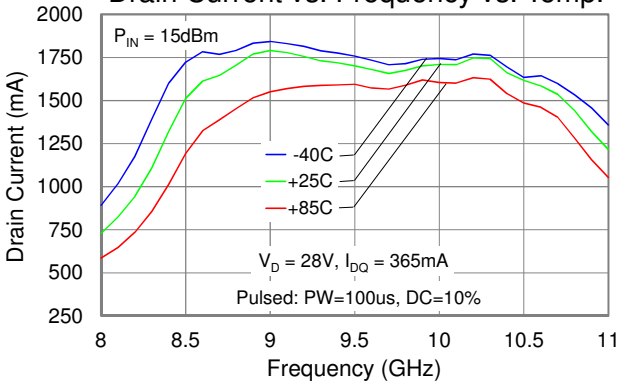
Power Gain vs. Input Power vs. Freq.



Drain Current vs. Input Power vs. Freq.

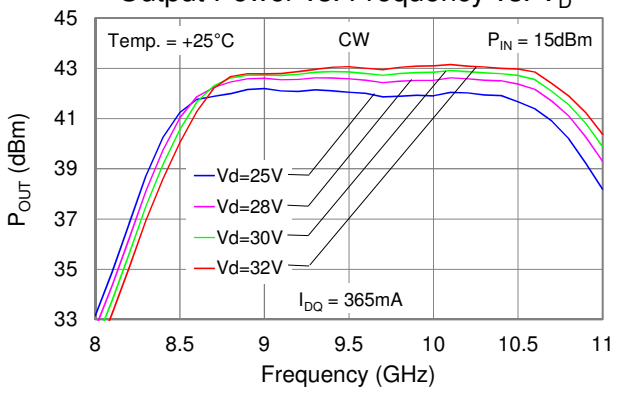


Drain Current vs. Frequency vs. Temp.

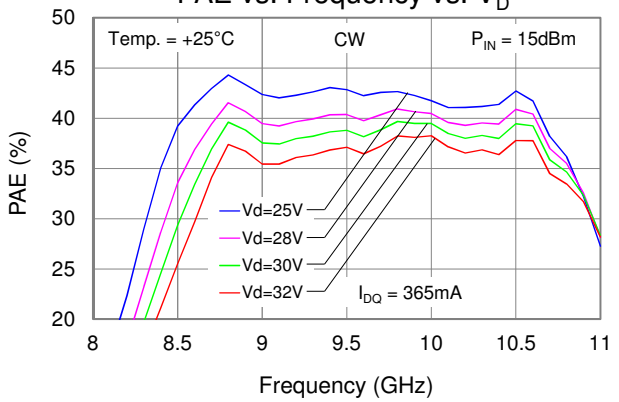


Typical Performance (CW Operation)

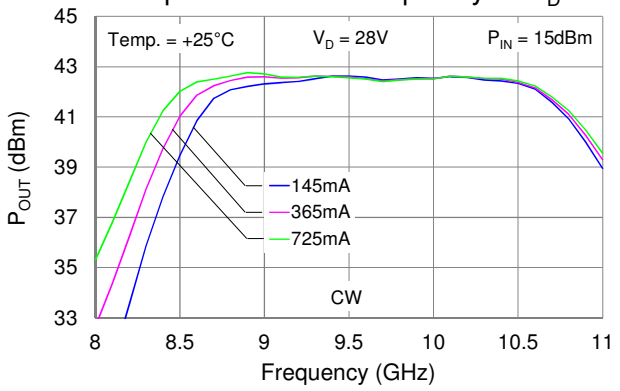
Output Power vs. Frequency vs. V_D



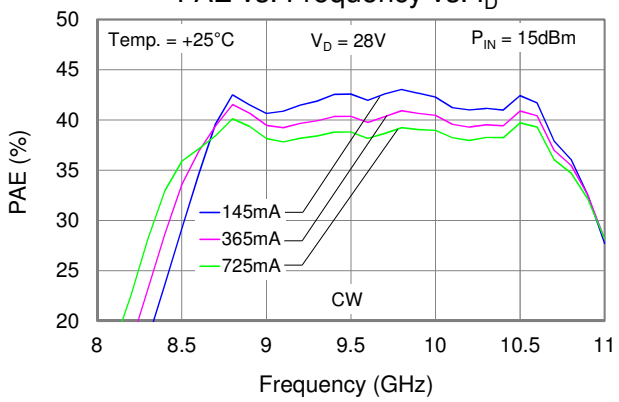
PAE vs. Frequency vs. V_D



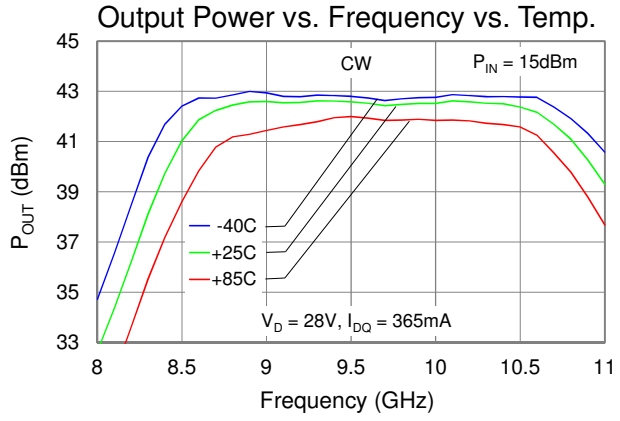
Output Power vs. Frequency vs. I_D



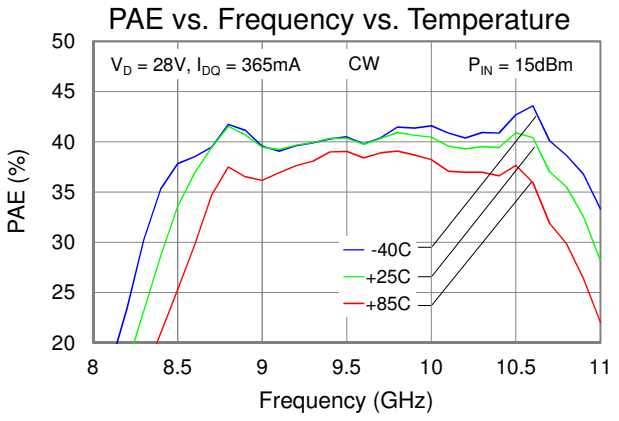
PAE vs. Frequency vs. I_D



Output Power vs. Frequency vs. Temp.

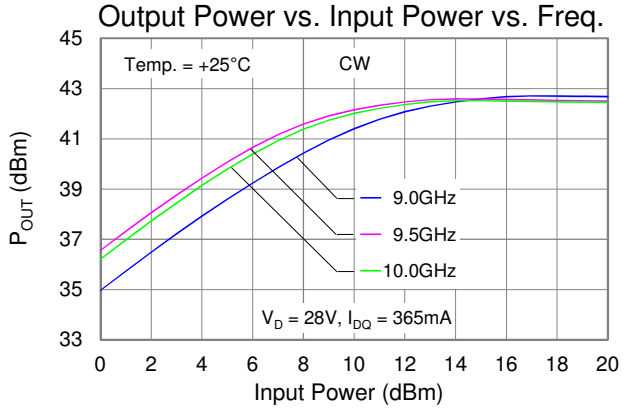


PAE vs. Frequency vs. Temperature

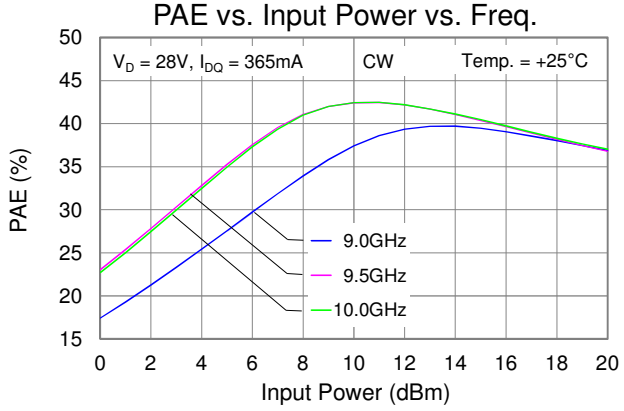


Typical Performance (CW Operation)

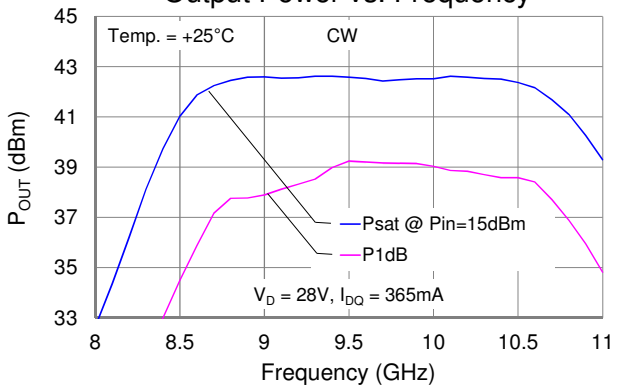
Output Power vs. Input Power vs. Freq.



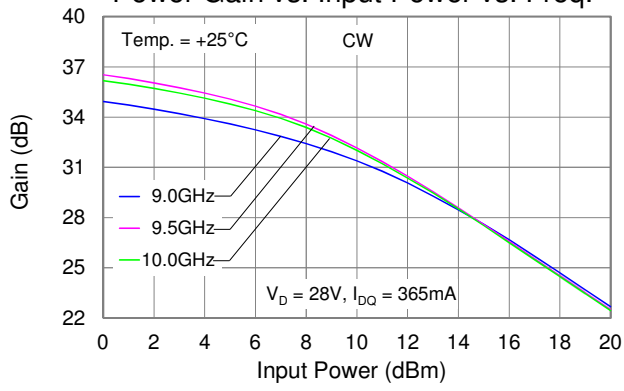
PAE vs. Input Power vs. Freq.



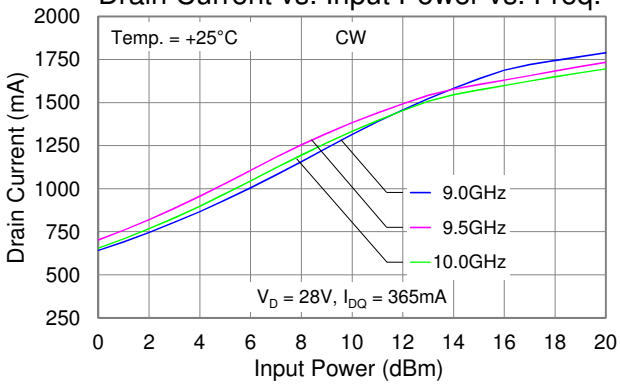
Output Power vs. Frequency



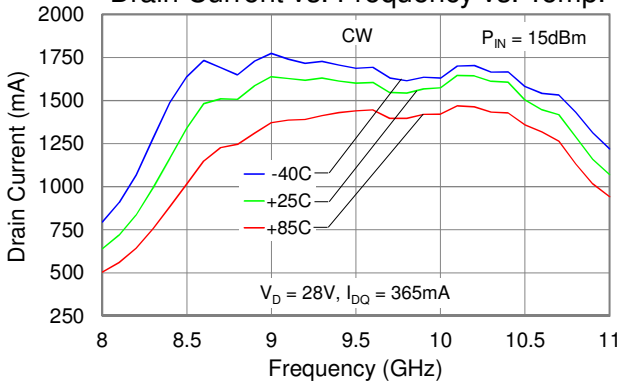
Power Gain vs. Input Power vs. Freq.



Drain Current vs. Input Power vs. Freq.

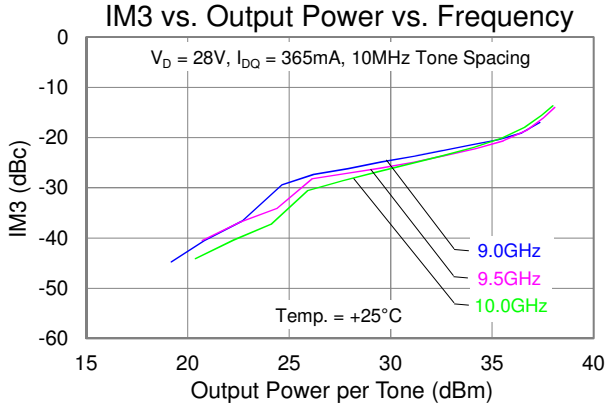


Drain Current vs. Frequency vs. Temp.

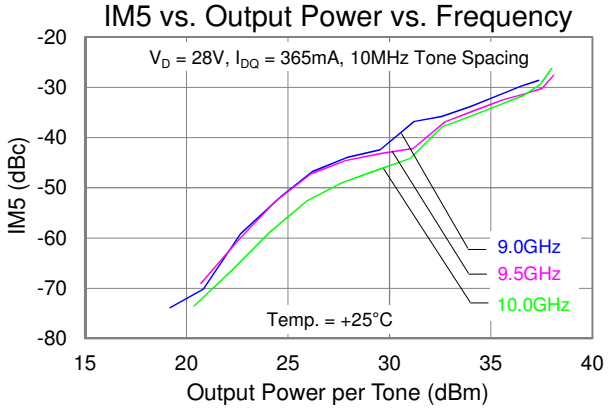


Typical Performance (Linearity)

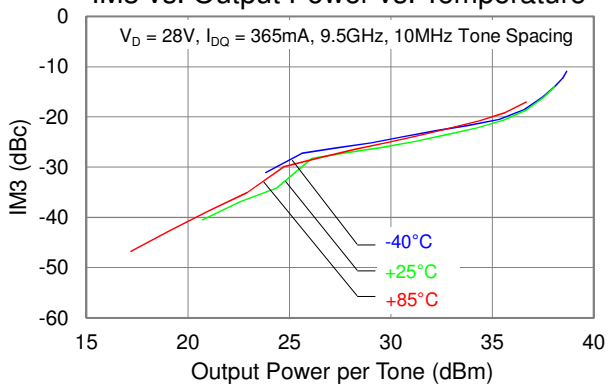
IM3 vs. Output Power vs. Frequency



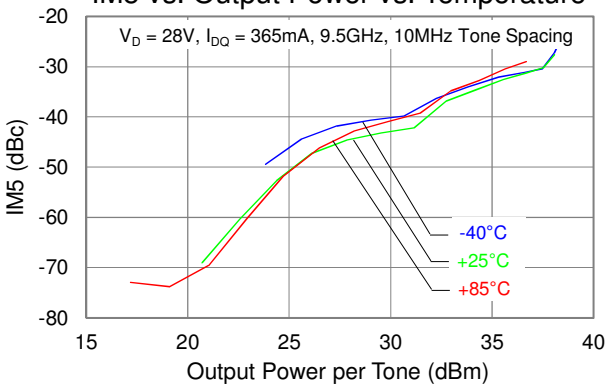
IM5 vs. Output Power vs. Frequency



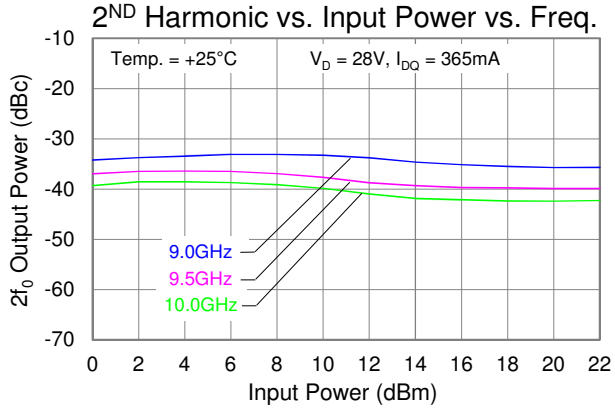
IM3 vs. Output Power vs. Temperature



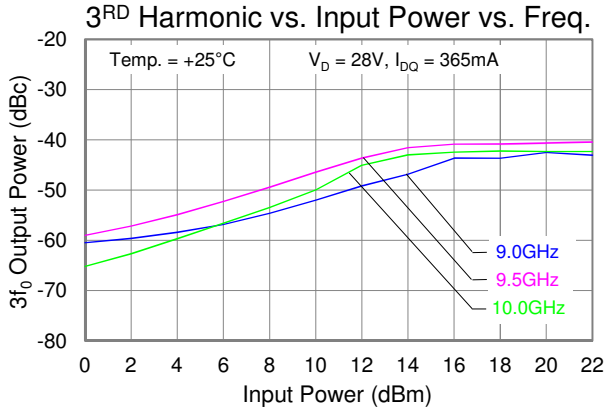
IM5 vs. Output Power vs. Temperature



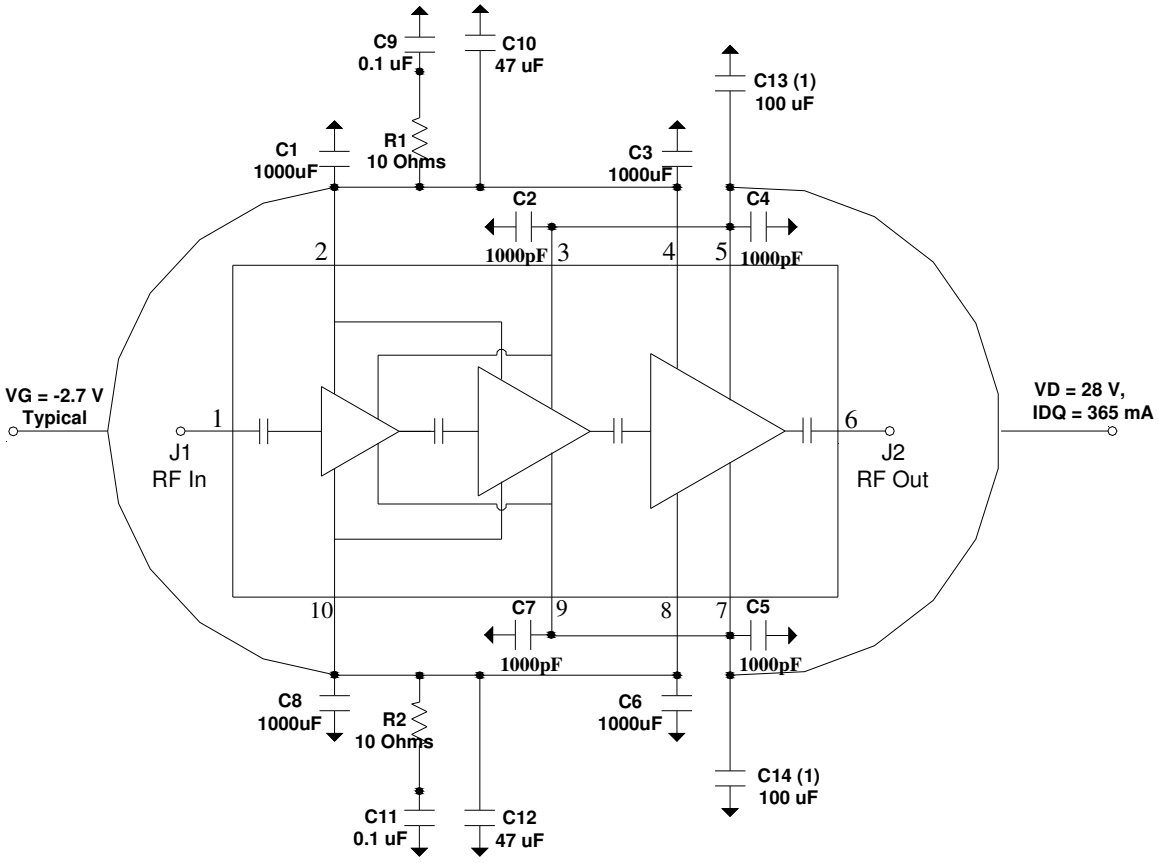
2ND Harmonic vs. Input Power vs. Freq.



3RD Harmonic vs. Input Power vs. Freq.



Application Circuit



Notes:

1. Remove caps for pulse operation. These caps are part of the cable harness for CW operation.

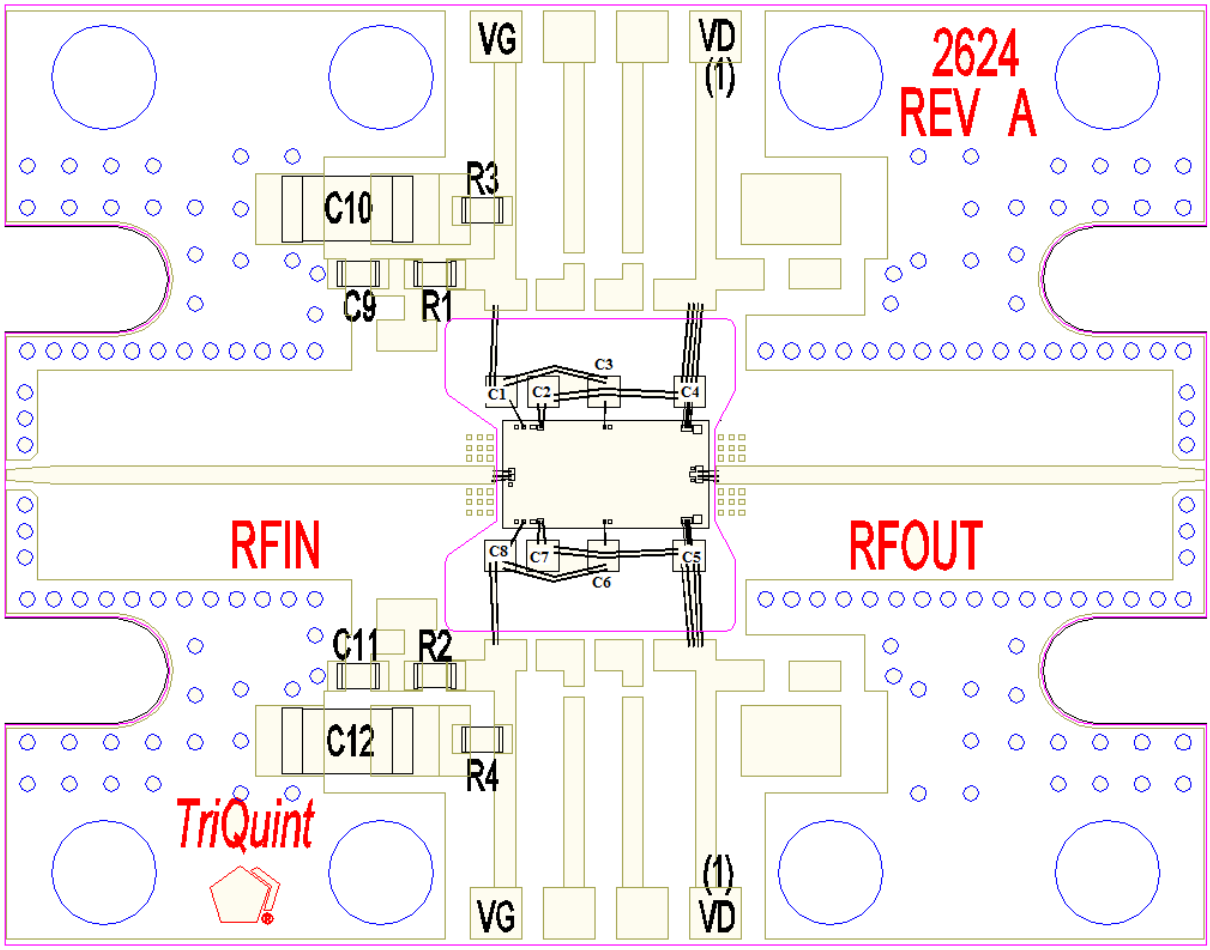
Bias-up Procedure

1. Set I_D limit to 1.9A, I_G limit to 12mA
2. Set V_G to -5.0V
3. Set V_D +28V
4. Adjust V_G more positive until I_{DQ} = 365mA (V_G ~ -2.7V Typical)
5. Apply RF signal

Bias-down Procedure

1. Turn off RF signal
2. Reduce V_G to -5.0V. Ensure I_{DQ} ~ 0mA
3. Set V_D to 0V
4. Turn off V_D supply
5. Turn off V_G supply

Evaluation Board (EVB) Layout Assembly



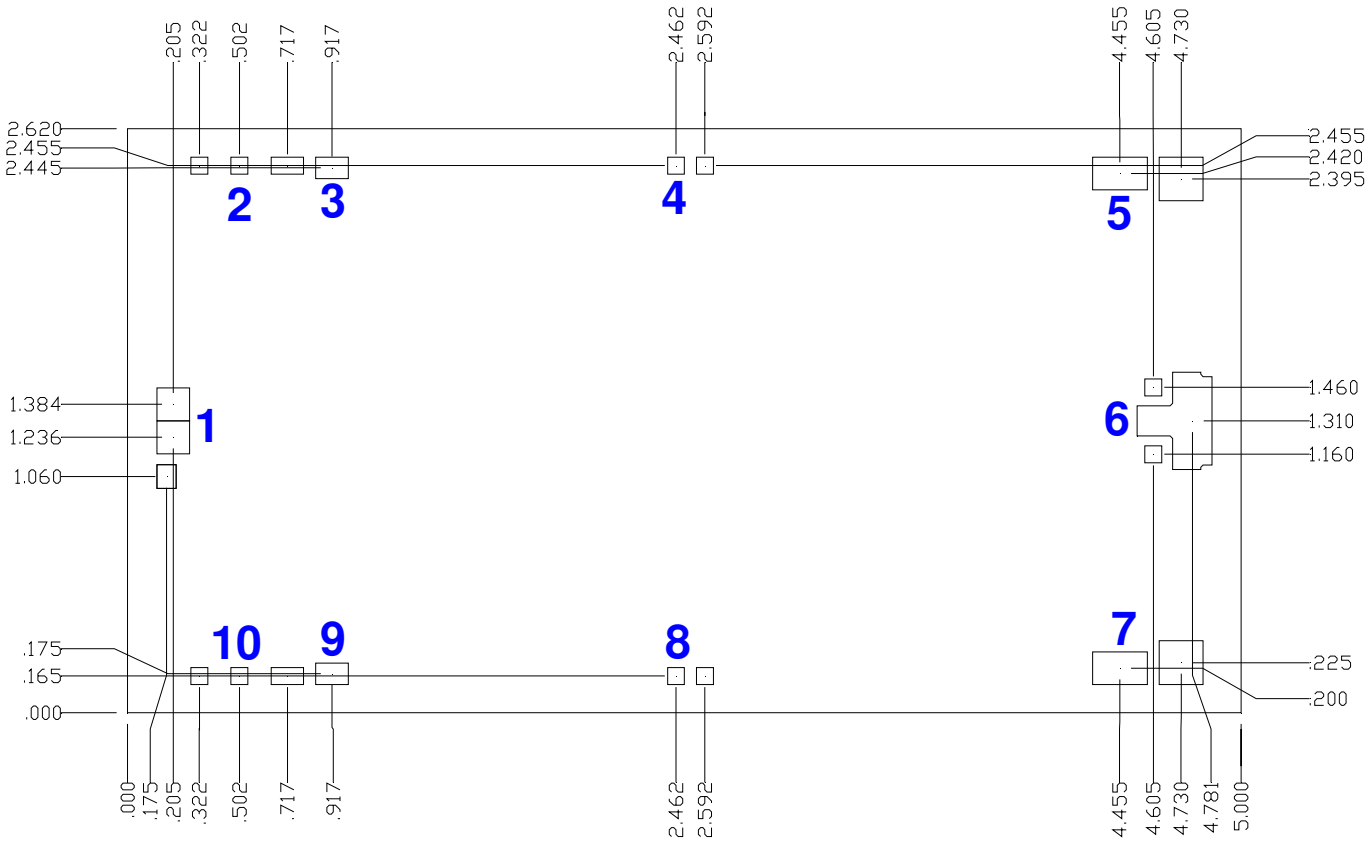
Notes:

1. 100uF/100V charge storage cap is needed on the drain. For pulsed operation this cap must be on the supply-side of the pulse-modulator.

Bill of Materials

Reference Design	Value	Description	Manufacturer	Part Number
C1 – C8	1000pF	SLC, 50V	Various	
C9, C11	0.1uF	Cap, 0402, 50V, 10%, X7R	Various	
C10, C12	47uF	Cap, 1206, 50V, 10%, X7R	Various	
R1 – R2	10Ω	Res, 0402	Various	
R3 – R4	0Ω	Res, 0402	Various	

Mechanical Drawing & Bond Pad Description



Unit: millimeters
Thickness: 0.10
Die x, y size tolerance: +/- 0.050
Chip edge to bond pad dimensions are shown to center of pad
Ground is backside of die

Bond Pad	Symbol	Pad Size	Description
1	RF In	0.150 x 0.300	RF Input; matched to 50Ω; DC Blocked
2, 8	V_{G1-2}	0.080 x 0.080	Gate voltage 1, bias network is required; see Application Circuit on page 10 as an example.
4,10	V_{G3}	0.080 x 0.080	Gate voltage 3, bias network is required; see Application Circuit on page 10 as an example.
3, 9	V_{D1-2}	0.150 x 0.100	Drain voltage 1, bias network is required; see Application Circuit on page 10 as an example.
5, 7	V_{D3}	0.250 x 0.150	Drain voltage 3, bias network is required; see Application Circuit on page 10 as an example.
6	RF Out	0.180 x 0.350	RF Output; matched to 50Ω; DC Blocked

Assembly Notes

Component placement and adhesive attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment (i.e. epoxy) can be used in low-power applications.
- Curing should be done in a convection oven; proper exhaust is a safety concern.

Reflow process assembly notes:

- Use AuSn (80/20) solder and limit exposure to temperatures above 300°C to 3-4 minutes, maximum.
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- Do not use any kind of flux.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- Force, time, and ultrasonic are critical parameters.
- Aluminum wire should not be used.
- Devices with small pad sizes should be bonded with 0.0007-inch wire.